

Trench IGBT Modules

SEMiX603GAR12E4p

Features

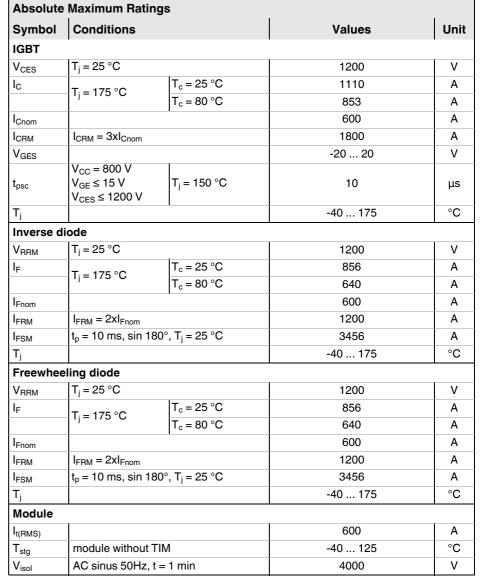
- · Homogeneous Si
- Trench = Trenchgate technology
- V_{CE(sat)} with positive temperature coefficient
- High short circuit capability
- Press-fit pins as auxiliary contacts
- Thermally optimized ceramic
- UL recognized, file no. E63532

Typical Applications*

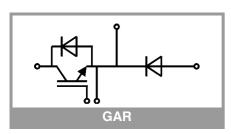
- · AC inverter drives
- UPS
- Renewable energy systems

Remarks

- Product reliability results are valid for T_i=150°C
- V_{isol} between temperature sensor and power section is only 2500V
- For storage and case temperature with TIM see document "TP(*) SEMiX 3p"



| Characteristics | | | | | | | |
|----------------------|--|-------------------------|------|------|------|------|--|
| Symbol | Conditions | | min. | typ. | max. | Unit | |
| IGBT | | | | | | • | |
| V _{CE(sat)} | $I_C = 600 \text{ A}$ $V_{GE} = 15 \text{ V}$ chiplevel | T _j = 25 °C | | 1.80 | 2.05 | V | |
| | | T _j = 150 °C | | 2.03 | 2.30 | V | |
| V _{CE0} | chiplevel | T _j = 25 °C | | 0.87 | 1.01 | V | |
| | | T _j = 150 °C | | 0.77 | 0.9 | V | |
| r _{CE} | V _{GE} = 15 V chiplevel | T _j = 25 °C | | 1.55 | 1.73 | mΩ | |
| | | T _j = 150 °C | | 2.1 | 2.3 | mΩ | |
| $V_{GE(th)}$ | V _{GE} =V _{CE} , I _C = 22.2 mA | | 5.3 | 5.8 | 6.3 | V | |
| I _{CES} | $V_{GE} = 0 \text{ V}, V_{CE} = 1200 \text{ V}, T_j = 25 ^{\circ}\text{C}$ | | | | 5 | mA | |
| C _{ies} | V _{CE} = 25 V V _{GE} = 0 V | f = 1 MHz | | 37.5 | | nF | |
| Coes | | f = 1 MHz | | 2.31 | | nF | |
| C _{res} | | f = 1 MHz | | 2.04 | | nF | |
| Q_G | V _{GE} = - 8 V+ 15 V | | | 3450 | | nC | |
| R _{Gint} | T _j = 25 °C | | | 1.2 | | Ω | |





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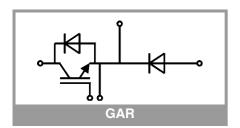
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|----------------------|--|-------------------------|------|-------|-------|------|
| Symbol | Conditions | | min. | typ. | max. | Unit |
| IGBT | | | | | | |
| t _{d(on)} | V _{CC} = 600 V | T _j = 150 °C | | 160 | | ns |
| t _r | $I_{\rm C} = 600 {\rm A}$ | T _j = 150 °C | | 80 | | ns |
| E _{on} | $V_{GE} = +15/-15 \text{ V}$ $R_{G \text{ on}} = 1.5 \Omega$ | T _j = 150 °C | | 64 | | mJ |
| t _{d(off)} | $R_{G \text{ off}} = 1.5 \Omega$ | T _j = 150 °C | | 540 | | ns |
| t _f | $di/dt_{on} = 7270 A/\mu s$ | T _j = 150 °C | | 130 | | ns |
| E _{off} | $\begin{array}{l} -\text{di/dt}_{\text{off}} = 4240 \text{ A/}\mu\text{s} \\ \text{du/dt} = 3500 \text{ V/}\mu\text{s} \\ \text{L}_{\text{s}} = 21 \text{ nH} \end{array}$ | T _j = 150 °C | | 76 | | mJ |
| R _{th(j-c)} | per IGBT | | | | 0.037 | K/W |
| R _{th(c-s)} | per IGBT (λ _{grease} =0 | .81 W/(m*K)) | | 0.035 | | K/W |
| R _{th(c-s)} | per IGBT, pre-applied phase change material | | | 0.025 | | K/W |
| Inverse d | iode | | | | | |
| $V_F = V_{EC} \\$ | $I_F = 600 \text{ A}$ | T _j = 25 °C | | 2.08 | 2.44 | V |
| | V _{GE} = 0 V chiplevel | T _j = 150 °C | | 2.08 | 2.34 | V |
| V_{F0} | chiplevel | T _j = 25 °C | | 1.39 | 1.59 | V |
| | | T _j = 150 °C | | 1.08 | 1.18 | V |
| r _F | chiplevel | T _j = 25 °C | | 1.16 | 1.42 | mΩ |
| | | T _j = 150 °C | | 1.67 | 1.93 | mΩ |
| I _{RRM} | I _F = 600 A | T _j = 150 °C | | 490 | | Α |
| Q_{rr} | di/dt _{off} = 7170 A/μs -V _{GE} = -15 V | T _j = 150 °C | | 93 | | μC |
| E _{rr} | $V_{CC} = 600 \text{ V}$ | T _j = 150 °C | | 32 | | mJ |
| R _{th(j-c)} | per diode | | | | 0.065 | K/W |
| R _{th(c-s)} | per diode (λ _{grease} =0.81 W/(m*K)) | | | 0.039 | | K/W |
| R _{th(c-s)} | per diode, pre-applied phase change material | | | 0.031 | | K/W |
| Freewhee | eling diode | | | | | |
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| R _{th(c-s)} | per diode, pre-applied phase change material | | | 0.031 | | K/W |





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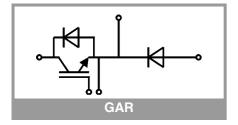
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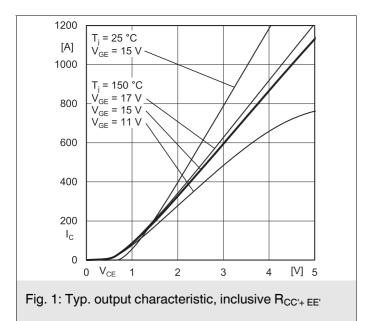
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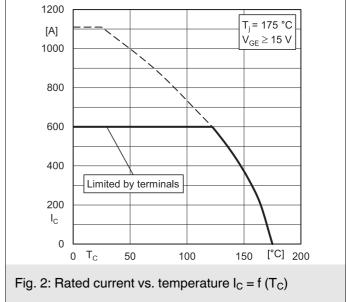
Remarks

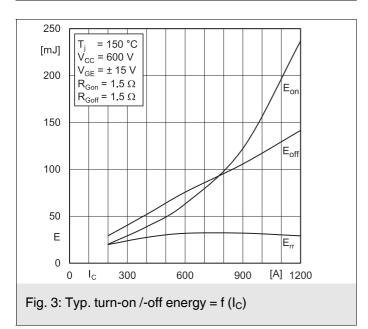
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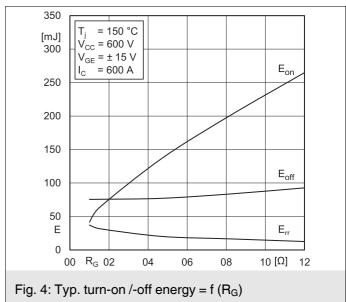
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|-----------------------|---|-------------------------|-------------|-------|------|------|--|--|
| Symbol | Conditions | | min. | typ. | max. | Unit | | |
| Module | | | | | | | | |
| L _{CE} | | | | 20 | | nH | | |
| R _{CC'+EE'} | measured per switch | T _C = 25 °C | | 1.2 | | mΩ | | |
| | | T _C = 125 °C | 1.65 | | | mΩ | | |
| Rth _{(c-s)1} | calculated without thermal coupling | | 0.009 | | | K/W | | |
| Rth _{(c-s)2} | including thermal coupling, Ts underneath module (λ_{grease} =0.81 W/(m*K)) | | 0.014 | | | K/W | | |
| Rth _{(c-s)2} | including thermal coupling, Ts underneath module, pre-applied phase change material | | | 0.011 | | K/W | | |
| Ms | to heat sink (M5) | | 3 | | 6 | Nm | | |
| M _t | | to terminals (M6) | 3 | | 6 | Nm | | |
| | | | | | | Nm | | |
| w | | | | | 350 | g | | |
| Temperat | ure Sensor | | | | | | | |
| R ₁₀₀ | T _c =100°C (R ₂₅ =5 kΩ) | | 493 ± 5% | | | Ω | | |
| B _{100/125} | R _(T) =R ₁₀₀ exp[B _{100/125} (1/T-1/T ₁₀₀)]; T[K]; | | 3550 ±2% | | | К | | |

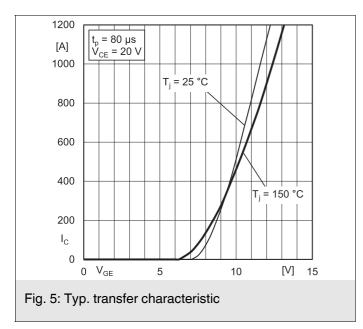


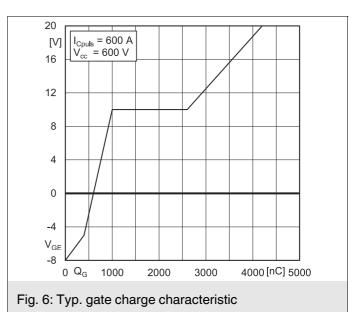


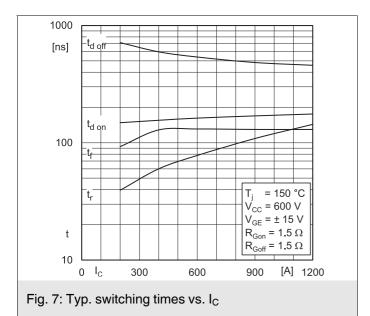


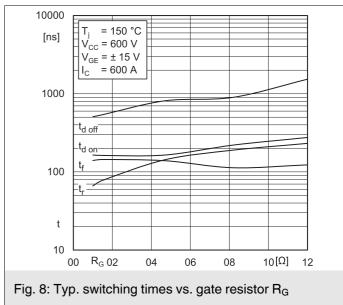


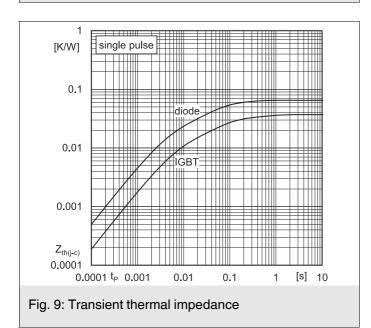


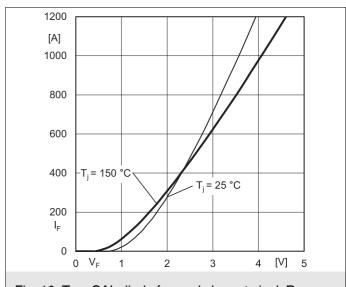












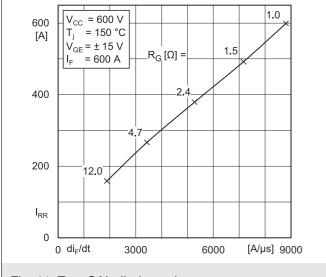


Fig. 10: Typ. CAL diode forward charact., incl. R_{CC'+ EE'}

1200

-900

+600

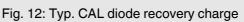
400-

[A/µs]10000

I_F [A] =

1.0

1.5



4.7

 $R_G[\Omega] =$

12.0

2.4

5000

Fig. 11: Typ. CAL diode peak reverse recovery current

150

[µC]

100

50

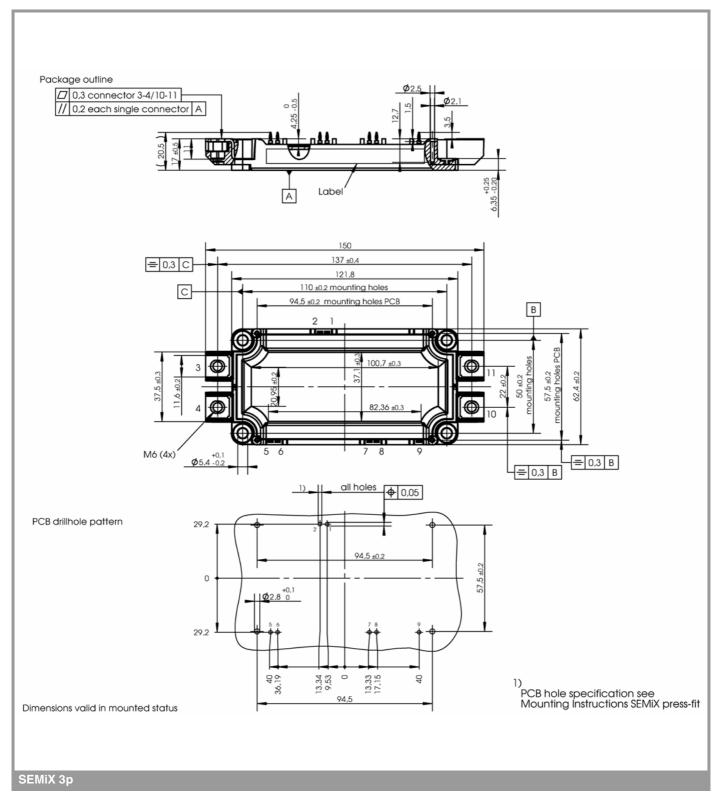
 Q_{rr}

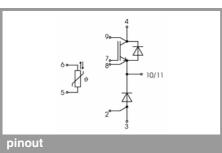
0 di_F/dt

 $V_{CC} = 600 \overline{V}$

 $V_{GE} = \pm 15 \text{ V}$

= 150 °C





This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, chapter IX.

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